

Mass Spectrometry

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Foreword

The idea for a Special Issue of the International Journal of Mass Spectrometry honoring the work of Dr. Yong-Ki Kim was born when Hans Deutsch and I (KHB) were visiting Tilmann Märk's group in Innsbruck in December of 2006. We were working on a paper that dealt with some aspects of the application of the Deutsch-Märk (DM) formalism for the calculation of ionization cross sections to a particular sub-group of atoms. One of the things we looked at was a comparison of experimental data with our calculations and with results of calculations using the Yong-Ki's BEB formalism that he had published earlier. The level of agreement was not what we expected and we were trying to figure out why. It struck us right then and there that were could no longer just shoot a quick e-mail to Yong-Ki and ask him what exactly he had done in his calculation and get an answer within a day. Our friend and colleague Yong-Ki Kim had died a few months earlier in a tragic car accident. In an instant, the atomic and molecular physics community had suffered the loss of a colleague whose work had stimulated and

energized the entire atomic physics community over a period of several decades.

Hans, Tilmann, and I with our DM formalism had been engaged in a friendly competition with Yong-Ki and his BEB formalism for the past 10 years and it is fair to say that each side greatly benefited from having the other side as a 'reality check' for their calculations. It took us a second to agree that the least we could do to honor Yong-Ki and his work was a compilation of research papers in areas close to Yong-Ki's activities published as a Special Issue in a journal, in which he had published a significant number of papers in the latter stage of his career. It is our pleasure and privilege to present the community with this Special Issue of the International Journal of Mass Spectrometry in honor of Dr. Yong-Ki Kim.

Guest Editors

Kurt H. Becker, Hans Deutsch, and Tilmann D. Märk

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